

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 02103-603001	Application No. 10/789,695
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Barret Lippey, et al.	
		Filing Date February 27, 2004	Group Art Unit 2862

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Issue / Pub Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	3,942,869	03-1976	Portner et al.			
	AB	5,497,207	03-1996	Kim			
	AC	5,526,063	06-1996	Joubert et al.			
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	AE	6,183,091	02-2001	Johnson et al.			
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	AG	6,648,475	11-2003	Roddy et al.			
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	AI	6,733,139	05-2004	Childers			
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	AL	6,956,702	10-2005	Pate			
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	AR	US2002/0145708	10-2002	Childers et al.			
	AS	US2002/186349	12-2002	Wichner			
	AT	US2003/0179346	09-2003	Mihara			
	AU	US2003/0002016	01-2003	Sellen et al.			
	AV	US2004/0044445	04-2002	Bohler			

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AW	0 493 863	07-1992	EPO				
	AX	0 490 391	06-1992	EPO				

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EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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### Foreign Patent Documents or Published Foreign Patent Applications

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							Yes	No
	AY	1341387	09-2003	EPO				
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Examiner Initial	Desig. ID	Document
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	AQQ	Young, L., "Multilayer Interference Filters with Narrow Stop Bands", Applied Optics, vol. 6(2), pp. 297-312 (02-1967).
	ARR	Pelletier et al., "Interference Filters with Multiple Peaks", J. Opt. Soc. Am., vol. 72(6), pp. 683-687 (06-1982).

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Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	ASS	EP Examination Report in Application No. 02102872.5, dated October 18, 2004.
	ATT	EP Examination Report in Application No. 02102872.5, dated May 13, 2005.
	AUU	EP Examination Report in Application No. 05101098.1, dated October 6, 2005.
	AVV	EP Examination Report in Application No. 02102872.5, dated March 17, 2006.
	AWW	International Search Report in Application No. PCT/US2006/000493, dated June 16, 2006.
	AXX	EP Examination Report in Application No. 05101098.1, dated February 16, 2007.
	AYY	EP Search Report in Application No. 05101103.9, dated March 2, 2007.
	AZZ	EP Partial Search Report in Application 07102106.7, dated May 18, 2007.
	AAAA	EP Search Report in Application 07102106.7, dated November 7, 2007.
	ABBB	CN Office Action in Application No. 02157897.4, dated June 8, 2007.
	ACCC	International Preliminary Report on Patentability in corresponding Application No. PCT/US2006/000493, dated July 19, 2007.
	ADDD	IN Examination Report in Application No. 1064/MUM/2002, dated 4/10/2008.
	AEEE	JP Examination Report in Application No. 2002-371849, dated March 27, 2008.
	AFFF	Office Action in related Application No. 10/931,608, dated August 25, 2005.
	AGGG	Office Action in related Application No. 10/931,608, dated April 17, 2006.
	AHHH	Office Action in related Application No. 11/033,214, dated December 15, 2006.
	AIII	Office Action in related Application No. 10/893,461, dated January 5, 2007.
	AJJJ	Office Action in related Application No. 11/548,373, dated April 26, 2007.
	AKKK	Office Action in related Application No. 10/893,461, dated May 7, 2007.
	ALLL	Office Action in related Application No. 11/033,214, dated September 13, 2007.
	AMMM	Office Action in related Application No. 11/127,531, dated September 27, 2007.
	ANNN	Office Action in related Application No. 10/893,461, dated February 15, 2008.
	AOOO	Office Action in related Application No. 11/548,373, dated April 1, 2008.
	APPP	

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